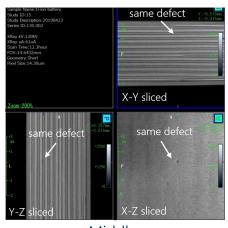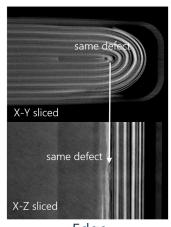# Failure Analysis of a Multilayered Battery Cell

Introduction

Failure analysis of battery products is routinely required to understand product defects and their impact on performance. X-ray CT is an effective failure analysis technique for multilayered battery cells. The use of the appropriate X-ray wavelength allows CT imaging to reconstruct a 3D image of the battery interior from a single automated sequence of measurements on an intact battery cell. In this case, a crack was observed in a failed battery using a CT Lab HX system.

X-ray CT images of battery interior

Middle

Edge

Related products

CT Lab HX

High-resolution benchtop microtomography of large samples